

<b>Notice of References Cited</b>	Application/Control No. 10/763,897	Applicant(s)/Patent Under Reexamination WAKATSUKI ET AL.	
	Examiner Christine T. Mui	Art Unit 1797	Page 1 of 1

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*	B	US-6,355,217	03-2002	Kiefersauer et al.	422/102
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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